•	Member of the Texas Instruments Widebus™ Family)r dgv pa (top view	
•	UBT [™] Transceiver Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or Clocked Modes	10EBY [1A [1Y [GND]	2 47 3 46] 1OEAB V _{CC} 1B GND
•	OEC™ Circuitry Improves Signal Integrity and Reduces Electromagnetic Interference (EMI)	2A [2Y [5 44 6 43	BIAS V _{CC} 2B V _{CC}
•	Compliant With VME64, 2eVME, and 2eSST Protocols		8 41	20EAB 3B1
•	Bus Transceiver Split LVTTL Port Provides Feedback Path for Control and Diagnostics Monitoring	GND [LE [3A2 [11 38	GND V _{CC} 3B2
•	I/O Interfaces Are 5-V Tolerant B-Port Outputs (–48 mA/64 mA)	3A3 [OE [14 35] 3В3 V _{CC}
•	Y and A-Port Outputs (–12 mA/12 mA)	GND [3A4 [] GND] 3B4
•	I _{off} , Power-Up 3-State, and BIAS V _{CC} Support Live Insertion	CLKBA [V _{CC} [CLKAB
•	Bus Hold on 3A-Port Data Inputs	3A5 [19 30	3B5
•	26- Ω Equivalent Series Resistor on 3A Ports and Y Outputs	3A6 [GND [21 28	3B6 GND
•	Flow-Through Architecture Facilitates Printed Circuit Board Layout	3A7 [3A8 [23 26	3B7 3B8
	Distributed Vac and GND Pins Minimize	DIR [24 25	□ v _{cc}

- Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)

description/ordering information

ORDERING INFORMATION

TA	PACKAGET		ORDERABLE PART NUMBER	TOP-SIDE MARKING
	TSSOP – DGG	Tape and reel	SN74VMEH22501ADGGR	VMEH22501A
–40°C to 85°C	TVSOP – DGV	Tape and reel	SN74VMEH22501ADGVR	VK501A
	VFBGA – GQL	Tape and reel	SN74VMEH22501AGQLR	VK501A

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



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description/ordering information (continued)

The SN74VMEH22501A 8-bit universal bus transceiver has two integral 1-bit three-wire bus transceivers and is designed for 3.3-V V_{CC} operation with 5-V tolerant inputs. The UBT™ transceiver allows transparent, latched, and flip-flop modes of data transfer, and the separate LVTTL input and outputs on the bus transceivers provide a feedback path for control and diagnostics monitoring. This device provides a high-speed interface between cards operating at LVTTL logic levels and VME64, VME64x, or VME320[†] backplane topologies.

The SN74VMEH22501A is pin-for-pin capatible to the VMEH22501, but operates at a wider operating temperature (-40°C to 85°C) range.

High-speed backplane operation is a direct result of the improved OEC™ circuitry and high drive that has been designed and tested into the VME64x backplane model. The B-port I/Os are optimized for driving large capacitive loads and include pseudo-ETL input thresholds (1/2 V_{CC} ±50 mV) for increased noise immunity. These specifications support the 2eVME protocols in VME64x (ANSI/VITA 1.1) and 2eSST protocols in VITA 1.5. With proper design of a 21-slot VME system, a designer can achieve 320-Mbyte transfer rates on linear backplanes and, possibly, 1-Gbyte transfer rates on the VME320 backplane.

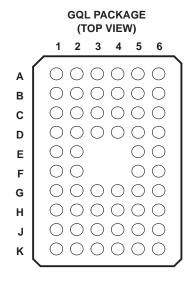
All inputs and outputs are 5-V tolerant and are compatible with TTL and 5-V CMOS inputs.

Active bus-hold circuitry holds unused or undriven 3A-port inputs at a valid logic state. Bus-hold circuitry is not provided on 1A or 2A inputs, any B-port input, or any control input. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.

This device is fully specified for live-insertion applications using Ioff, power-up 3-state, and BIAS V_{CC}. The Ioff circuitry prevents damaging current to backflow through the device when it is powered off/on. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict. The BIAS V_{CC} circuitry precharges and preconditions the B-port input/output connections, preventing disturbance of active data on the backplane during card insertion or removal, and permits true live-insertion capability.

When V_{CC} is between 0 and 1.5 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, output-enable (OE and OEBY) inputs should be tied to V_{CC} through a pullup resistor and output-enable (OEAB) inputs should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the drive capability of the device connected to this input.

[†] VME320 is a patented backplane construction by Arizona Digital, Inc.



terminal assignments

	1	2	3	4	5	6
Α	1OEBY	NC	NC	NC	NC	10EAB
в	1Y	1A	GND	GND	VCC	1B
С	2Y	2A	VCC	VCC	$BIAS V_{CC}$	2B
D	3A1	2OEBY	GND	GND	20EAB	3B1
Е	3A2	LE			V _{CC}	3B2
F	3A3	OE			V _{CC}	3B3
G	3A4	CLKBA	GND	GND	CLKAB	3B4
н	3A5	3A6	VCC	VCC	3B6	3B5
J	3A7	3A8	GND	GND	3B8	3B7
κ	DIR	NC	NC	NC	NC	V _{CC}

NC – No internal connection



functional description

The SN74VMEH22501A is a high-drive (-48/64 mA), 8-bit UBT transceiver containing D-type latches and D-type flip-flops for data-path operation in transparent, latched, or flip-flop modes. Data transmission is true logic. The device is uniquely partitioned as 8-bit UBT transceivers with two integrated 1-bit three-wire bus transceivers.

functional description for two 1-bit bus transceivers

The OEAB inputs control the activity of the 1B or 2B port. When OEAB is high, the B-port outputs are active. When OEAB is low, the B-port outputs are disabled.

Separate 1A and 2A inputs and 1Y and 2Y outputs provide a feedback path for control and diagnostics monitoring. The OEBY inputs control the 1Y or 2Y outputs. When OEBY is low, the Y outputs are active. When OEBY is high, the Y outputs are disabled.

The \overline{OEBY} and OEAB inputs can be tied together to form a simple direction control where an input high yields A data to B bus and an input low yields B data to Y bus.

INPUTS OEAB OEBY		OUTPUT	MODE
		OUTPUT	MODE
L	Н	Z	Isolation
Н	Н	A data to B bus	True dei en
L	L	B data to Y bus	True driver
Н	L	A data to B bus, B data to Y bus	True driver with feedback path

1-BIT BUS TRANSCEIVER FUNCTION TABLE



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functional description for 8-bit UBT transceiver

The 3A and 3B data flow in each direction is controlled by the OE and direction-control (DIR) inputs. When OE is low, all 3A- or 3B-port outputs are active. When OE is high, all 3A- or 3B-port outputs are in the high-impedance state.

FUNCTION TABLE						
INPUTS						
OE	DIR	OUTPUT				
Н	Х	Z				
L	Н	3A data to 3B bus				
LL		3B data to 3A bus				

The UBT transceiver functions are controlled by latch-enable (LE) and clock (CLKAB and CLKBA) inputs. For 3A-to-3B data flow, the UBT operates in the transparent mode when LE is high. When LE is low, the 3A data is latched if CLKAB is held at a high or low logic level. If LE is low, the 3A data is stored in the latch/flip-flop on the low-to-high transition of CLKAB.

The UBT transceiver data flow for 3B to 3A is similar to that of 3A to 3B, but uses CLKBA.

	INP	UTS		OUTPUT	MODE				
OE	LE	CLKAB	3A	3B	MODE				
Н	Х	Х	Х	Z	Isolation				
L	L	Н	Х	в ₀ ‡					
L	L	L	Х	в ₀ ‡ в ₀ §	Latched storage of 3A data				
L	Н	Х	L	L	True for a second second				
L	Н	Х	Н	н	True transparent				
L	L	\uparrow	L	L					
L	L	\uparrow	Н	Н	Clocked storage of 3A data				

UBT TRANSCEIVER FUNCTION TABLE[†]

[†] 3A-to-3B data flow is shown; 3B-to-3A data flow is similar, but uses CLKBA.

[‡]Output level before the indicated steady-state input conditions were established, provided that CLKAB was high before LE went low

§ Output level before the indicated steady-state input conditions were established

The UBT transceiver can replace any of the functions shown in Table 1.

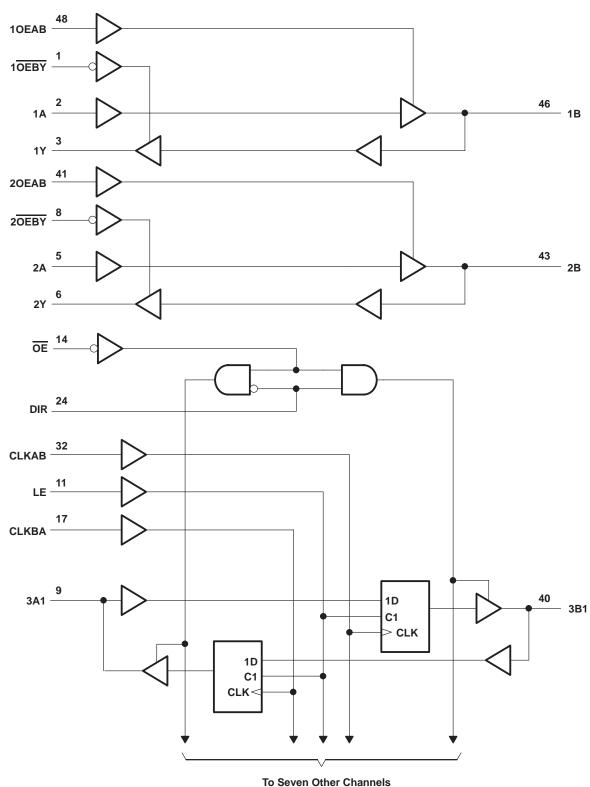
Table 1. SN74VMEH22501A UBT Transceiver Replacement Functions

FUNCTION	8 BIT		
Transceiver	'245, '623, '645		
Buffer/driver	'241, '244, '541		
Latched transceiver	'543		
Latch	'373, '573		
Registered transceiver	'646, '652		
Flip-flop '374, '574			
SN74VMEH22501A UBT transceiver replaces all above functions			



8-BIT UNIVERSAL BUS TRANSCEIVER AND TWO 1-BIT BUS TRANSCEIVERS WITH SPLIT LVTTL PORT, FEEDBACK PATH, AND 3-STATE OUTPUTS SCES620 - DECEMBER 2004 **SN74VMEH22501A**





Pin numbers shown are for the DGG and DGV packages.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} and BIAS V _{CC} Input voltage range, V _I (see Note 1)	
Voltage range applied to any output in the high-impedance or power-off state, V _O (see Note 1)	–0.5 V to 7 V
(see Note 1): 3A port or Y output	
Output current in the low state, I _O : 3A port or Y output B port	50 mA
Output current in the high state, I _O : 3Å port or Y output B port	
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$): B port	
Package thermal impedance, θ_{JA} (see Note 2): DGG package	
DGV package	
GQL package	
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Notes 3 and 4)

			MIN	TYP	MAX	UNIT	
V _{CC} , BIAS V _{CC}	Supply voltage		3.15	3.3	3.45	V	
VI		Control inputs or A port		VCC	5.5		
	Input voltage	B port		VCC	5.5	V	
Maria	Litely local females from	Control inputs or A port	2				
VIH	High-level input voltage	B port	0.5 V _{CC} + 50 mV			- V	
	Law law of Second configure	Control inputs or A port			0.8		
VIL	Low-level input voltage	B port		C	0.5 V _{CC} – 50 mV	V	
IIK	Input clamp current				-18	mA	
	LPak land autout annual	3A port and Y output			-12		
ЮН	High-level output current	B port			-48	mA	
		3A port and Y output			12		
IOL	Low-level output current	B port			64	mA	
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled			10	ns/V	
$\Delta t / \Delta V_{CC}$	Power-up ramp rate		20			μs/V	
TA	Operating free-air temperature		-40		85	°C	

NOTES: 3. All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

4. Proper connection sequence for use of the B-port I/O precharge feature is GND and BIAS $V_{CC} = 3.3$ V first, I/O second, and $V_{CC} = 3.3$ V last, because the BIAS V_{CC} precharge circuitry is disabled when any V_{CC} pin is connected. The control inputs can be connected anytime, but normally are connected during the I/O stage. If B-port precharge is not required, any connection sequence is acceptable, but generally, GND is connected first.



electrical characteristics over recommended operating free-air temperature range for A and B ports (unless otherwise noted)

	PARAMETER	TEST CO	ONDITIONS	MIN	TYP†	MAX	UNIT
VIK		V _{CC} = 3.15 V,	lı = -18 mA			-1.2	V
	3A port, any B ports, and Y outputs	$V_{CC} = 3.15 V \text{ to } 3.45 V,$	I _{OH} = -100 μA	V _{CC} -0.2			
V _{OH}	3A port and Y outputs	V _{CC} = 3.15 V	$I_{OH} = -6 \text{ mA}$ $I_{OH} = -12 \text{ mA}$	2.4			V
	Any B port	V _{CC} = 3.15 V	$I_{OH} = -24 \text{ mA}$ $I_{OH} = -48 \text{ mA}$	2.4			
	3A port, any B ports, and Y outputs	$V_{CC} = 3.15 V \text{ to } 3.45 V,$	l _{OL} = 100 μA			0.2	
VOL	3A port and Y outputs	V _{CC} = 3.15 V	$I_{OL} = 6 \text{ mA}$ $I_{OL} = 12 \text{ mA}$			0.55 0.8	V
UL	Any B port	V _{CC} = 3.15 V	$I_{OL} = 24 \text{ mA}$ $I_{OL} = 48 \text{ mA}$ $I_{OL} = 64 \text{ mA}$			0.4 0.55 0.6	-
1j	Control inputs,	V _{CC} = 3.45 V,	$V_{I} = V_{CC} \text{ or } GND$			±1	μA
I _{OZH} ‡	1A and 2A 3A port, any B port, and Y outputs	$V_{CC} = 0 \text{ or } 3.45 \text{ V},$ $V_{CC} = 3.45 \text{ V},$	$V_{I} = 5.5 V$ $V_{O} = V_{CC} \text{ or } 5.5 V$			5 5	μΑ
I _{OZL} ‡	3A port and Y outputs	V _{CC} = 3.45 V,	V _O = GND			-5	μA
I _{off}	Any B port	$V_{CC} = 0$, BIAS $V_{CC} = 0$,	$V_{\rm I}$ or $V_{\rm O} = 0$ to 5.5 V			-20 ±10	μΑ
ι _{BHL} §	3A port	$V_{CC} = 3.15 V,$	V _I = 0.8 V	75		10	μ <u>Α</u>
I _{BHH} ¶	3A port	$V_{CC} = 3.15 V,$	V ₁ = 2 V	-75			μA
IBHLO#	3A port	V _{CC} = 3.45 V,	$V_{I} = 0$ to V_{CC}	500			μA
Івнно	3A port	V _{CC} = 3.45 V,	$V_I = 0$ to V_{CC}	-500			μΑ
IOZ(PU/F	۲ 0)*	$V_{CC} \le 1.3 \text{ V}, V_O = \frac{0.5}{\text{VI}} \text{ V}$ to $V_I = \text{GND or } V_{CC}, \overline{\text{OE}} = \text{dor}$	V _{CC} , n't care			±10	μΑ

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25° C.

 \ddagger For I/O ports, the parameters IOZH and IOZL include the input leakage current.

§ The bus-hold circuit can sink at least the minimum low sustaining current at VIL max. IBHL should be measured after lowering VIN to GND, then raising it to VII max.

The bus-hold circuit can source at least the minimum high sustaining current at VIH min. IBHH should be measured after raising VIN to VCC, then lowering it to VIH min.

An external driver must source at least IBHLO to switch this node from low to high.

An external driver must sink at least IBHHO to switch this node from high to low.

*High-impedance state during power up or power down



electrical characteristics over recommended operating free-air temperature range for A and B ports (unless otherwise noted) (continued)

PARAMETER		TEST CO	NDITIONS	MIN TYP [†]	MAX	UNIT
			Outputs high	30		
ICC		$V_{CC} = 3.45 \text{ V}, I_{O} = 0,$ VI = V_{CC} or GND	Outputs low		30	mA
			Outputs disabled		30	
ICCD		$V_{CC} = 3.45 \text{ V}, \text{ I}_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND},$	Outputs enabled	76		μΑ/ clock
		One data input switching at one-half clock frequency, 50% duty cycle	Outputs disabled	19		MHz/ input
ΔI _{CC} □		V_{CC} = 3.15 V to 3.45 V, One Other inputs at V _{CC} or GND	V_{CC} = 3.15 V to 3.45 V, One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND		750	μA
	1A and 2A inputs	N/ 0.45 Y/ 0		2.8		
Ci	Control inputs	V _I = 3.15 V or 0		2.6		pF
Co	1Y or 2Y outputs	V _O = 3.15 V or 0		5.6		pF
0	3A port		V _O = 3.3 V or 0	7.9		pF
Cio	Any B port	V _{CC} = 3.3 V,	vO = 3.3 v 01 0	11	12.5	μr

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. [□] This is the increase in supply current for each input that is at the specified TTL voltage level, rather than V_{CC} or GND.

live-insertion specifications over recommended operating free-air temperature range for B port

PARAMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
	$V_{CC} = 0$ to 3.15 V,	BIAS V _{CC} = 3.15 V to 3.45 V,	$I_{O(DC)} = 0$			5	mA
I _{CC} (BIAS V _{CC})	$V_{CC} = 3.15 \text{ V to } 3.45 \text{ V}^{\ddagger},$	BIAS V _{CC} = 3.15 V to 3.45 V,	$I_{O(DC)} = 0$			10	μA
Vo	$V_{CC} = 0,$	BIAS V _{CC} = 3.15 V to 3.45 V		1.3	1.5	1.7	V
		$V_{O} = 0,$	BIAS V_{CC} = 3.15 V	-20		-100	•
10	$V_{CC} = 0$	V _O = 3 V,	BIAS V_{CC} = 3.15 V	20		100	μA

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

⁺ V_{CC} - 0.5 V < BIAS V_{CC}



timing requirements over recommended operating conditions for UBT transceiver (unless otherwise noted) (see Figures 1 and 2)

				MIN	MAX	UNIT
fclock	Clock frequency				120	MHz
	Pulse duration	LE high		2.5		
tw	CLK high or low			3		ns
			Data high	2.1		
		3A before CLK↑	Data low	2.2		
			CLK high	2		
	Setup time	3A before LE↓	CLK low	2		
t _{su}			Data high	2.5		ns
		3B before CLK↑	Data low	2.7		
			CLK high	2		
		3B before LE↓	CLK low	2		
			Data high	0		
		3A after CLK↑	Data low	0		
			CLK high	1		
		3A after LE↓	CLK low	1		ns
th	Hold time		Data high	0		
		3B after CLK↑	Data low	0		
			CLK high	1		
		3B after LE↓	CLK low	1		

switching characteristics over recommended operating conditions for bus transceiver function (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	ΤΥΡ Μ	
^t PLH	11 01	4D - = 0D	4.8	8	3.9
^t PHL	1A or 2A	1B or 2B	4.5	7	'.8 ns
^t PLH	1A or 2A	4V or 0V	6.2	14	1.5
^t PHL	TA OF ZA	1Y or 2Y	6.1		13 ^{ns}
^t PZH		4D at 0D	3.9	8	3.1
tPZL	OEAB	1B or 2B	3.7	7	'.4 ^{ns}
^t PHZ	OEAB	4D at 0D	3.3	ę).7
tPLZ		1B or 2B	1.8	2	.8 ns
tr	Transition time, E	3 port (10%–90%)		4.3	ns
t _f	Transition time, E	3 port (90%–10%)		4.3	ns
^t PLH		41/ 01/	1.6	Ę	5.6
^t PHL	1B of 2B	1Y or 2Y	1.6	Ę	5.6 ns
^t PZH		4V or 0V	1.2	Ę	5.6
tPZL	OEBY	1Y or 2Y	1.8	2	l.9 ns
^t PHZ	OEBY	1Y or 2Y	0.9	Ę	5.4
^t PLZ	OLDT	IT OF ZT	1.4	2	l.5 ns



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switching characteristics over recommended operating conditions for UBT transceiver (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	ΤΥΡ ΜΑ	
fmax			120		MHz
^t PLH	24	0.0	5.1	9.3	
^t PHL	3A	3B	4.7	8.3	3 ns
^t PLH		20	5.5	10.0	
^t PHL	LE	3B	4.9	8.	, ns
^t PLH	CLKAB	20	5.8	10.1	
^t PHL		3B	4.2	8.4	ns 1
^t PZH	OE	20	4.2	9.3	
^t PZL	OE	3B	3.2	8.	5 ns
^t PHZ	ŌE	20	4.2	9.3	
^t PLZ		3B	2.4	5.	ns
tr	Transition time, B	port (10%–90%)		4.3	ns
tf	Transition time, B	port (90%–10%)		4.3	ns
^t PLH	20		1.5	5.9	
^t PHL	3B	ЗА	1.7	5.9) ns
^t PLH		0.4	1.7	5.9	
^t PHL	LE	ЗА	1.7	5.9) ns
^t PLH		0.4	1.1	5.	
^t PHL	CLKBA	ЗА	1.4	5.5	5 ns
^t PZH	ŌĒ	24	1.5	6.2	
^t PZL	UE	ЗА	2.1	5.	5 ns
^t PHZ	ŌĒ	24	0.8	6.2	
^t PLZ	UE	ЗА	2.3	5.0	ns S

skew characteristics for bus transceiver for specific worst-case V_{CC} and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN MAX	UNIT
^t sk(LH)	1A or 2A	1B or 2B	0.8	
^t sk(HL)	TA OF ZA	IB UI 2B	0.7	ns
^t sk(LH)	1B or 2B 1Y or 2Y	0.7		
^t sk(HL)		IT UI ZT	0.7	ns
4 †	1A or 2A	1B or 2B	3.9	
^t sk(t) [†]	1B or 2B	1Y or 2Y	1.5	ns
++()	1A or 2A	1B or 2B	3.6	
^t sk(pp)	1B or 2B	1Y or 2Y	1.4	ns

tsk(t) - Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V_{CC} and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [tsk(t)].



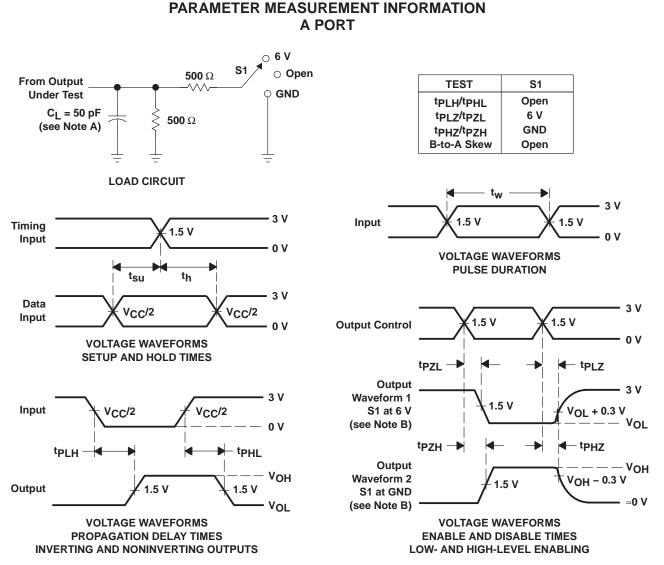
skew characteristics for UBT for specific worst-case V_{CC} and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN MAX	UNIT
^t sk(LH)	3A	3B	1.4	
^t sk(HL)	3A	ЭВ	1.1	ns
^t sk(LH)	CLKAB	3B	0.8	
^t sk(HL)	CLKAD	ЭD	0.8	ns
^t sk(LH)		0.7		
^t sk(HL)	ЗВ	3A	0.6	ns
^t sk(LH)		0.7		
^t sk(HL)	CLKBA	3A	0.6	ns
	3A	3B	3.9	
tt	CLKAB	3B	3.9	-
t _{sk(t)} †	3B	ЗA	1.6	ns
	CLKBA	3A	1.2	
	3A	3B	3.6	
* • • • •	CLKAB	3B	3.5	
^t sk(pp)	3B	3A	1.3	ns
	CLKBA	3A	1.2	

tsk(t) - Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V_{CC} and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [tsk(t)].



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NOTES: A. C_L includes probe and jig capacitance.

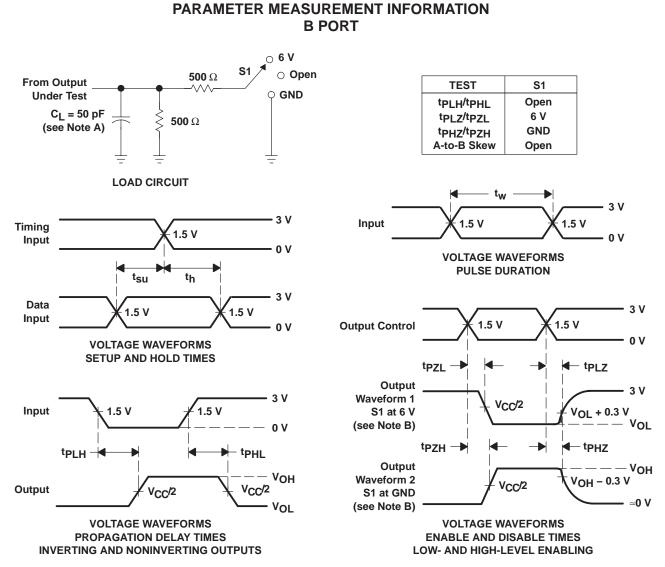
B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \approx 10 MHz, Z_O = 50 Ω , t_f \approx 2 ns, t_f \approx 2 ns.

D. The outputs are measured one at a time, with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms





NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control.
- Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \approx 10 MHz, Z_O = 50 Ω , t_f \approx 2 ns, t_f \approx 2 ns.

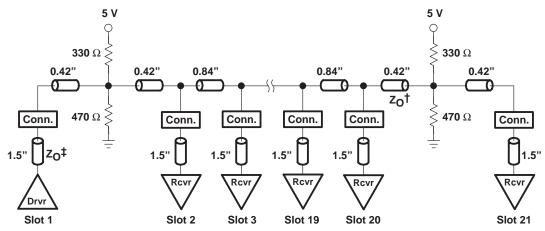
D. The outputs are measured one at a time, with one transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms



DISTRIBUTED-LOAD BACKPLANE SWITCHING CHARACTERISTICS

The preceding switching characteristics tables show the switching characteristics of the device into the lumped load shown in the parameter measurement information (PMI) (see Figures 1 and 2). All logic devices currently are tested into this type of load. However, the designer's backplane application probably is a distributed load. For this reason, this device has been designed for optimum performance in the VME64x backplane as shown in Figure 3.



[†] Unloaded backplane trace natural impedence (Z_O) is 45 Ω . 45 Ω to 60 Ω is allowed, with 50 Ω being ideal. [‡] Card stub natural impedence (Z_O) is 60 Ω .

Figure 3. VME64x Backplane

The following switching characteristics tables derived from TI-SPICE models show the switching characteristics of the device into the backplane under full and minimum loading conditions, to help the designer better understand the performance of the VME device in this typical backplane. See www.ti.com/sc/etl for more information.

driver in slot 11, with receiver cards in all other slots (full load)

switching characteristics over recommended operating conditions for bus transceiver function (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	ΤΥΡ§	МАХ	UNIT
^t PLH	40	1B or 2B	5.9		8.5	
^t PHL	1A or 2A		5.5		8.7	ns
tr¶	Transition time, B	Transition time, B port (10%–90%)		8.6	11.4	ns
tf¶	Transition time, B	port (90%–10%)	8.9	9	10.8	ns

[§] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models. ¶ All t_r and t_f times are taken at the first receiver.



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driver in slot 11, with receiver cards in all other slots (full load) (continued)

switching characteristics over recommended operating conditions for UBT (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	түр†	MAX	UNIT
^t PLH	24	20	6.2		8.9	
^t PHL	ЗА	3B	5.6		9	ns
^t PLH		20	6.1		9.1	
^t PHL	LE	3B	5.6		9	ns
^t PLH	CLKAB	20	6.2		9.1	
^t PHL	CLKAB	3B	5.7		9	ns
t _r ‡	Transition time, B	Transition time, B port (10%–90%)		8.6	11.4	ns
t _f ‡	Transition time, B	port (90%–10%)	8.9	9	10.8	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

[‡] All t_r and t_f times are taken at the first receiver.

skew characteristics for bus transceiver for specific worst-case V_{CC} and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	ΜΙΝ ΤΥΡ [†] ΜΑΧ	UNIT
^t sk(LH)	1A or 2A 1B or 2B	2.5		
^t sk(HL)	TA OF ZA	TB of 2B	3	ns
tsk(t)§	1A or 2A	1B or 2B	1	ns
^t sk(pp)	1A or 2A	1B or 2B	0.5 3.4	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

§ tsk(t) - Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V_{CC} and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [tsk(t)].

skew characteristics for UBT for specific worst-case V_{CC} and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	ΜΙΝ ΤΥΡ [†] ΜΑΧ	UNIT
^t sk(LH)		20	2.4	
^t sk(HL)	JA JA	3B	3.4	ns
^t sk(LH)	CLKAB	20	2.7	
^t sk(HL)	CLKAD	3B	3.4	ns
4 8	3A	3B	1	
t _{sk(t)} §	CLKAB	3B	1	ns
+	ЗА	3B	0.5 3.4	
^t sk(pp)	CLKAB	3B	0.6 3.5	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

Stsk(t) - Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V_{CC} and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [tsk(t)].



driver in slot 1, with one receiver in slot 21 (minimum load)

switching characteristics over recommended operating conditions for bus transceiver function (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	түр†	MAX	UNIT
^t PLH	44 24	4D or 0D	5.5		7.4	
^t PHL	1A or 2A	1B or 2B	5.3		7.4	ns
t _r ‡	Transition time, B	Transition time, B port (10%–90%)		3.4	4.4	ns
tf‡	Transition time, B	port (90%–10%)	3.7	3.4	4.8	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

[‡] All t_r and t_f times are taken at the first receiver.

switching characteristics over recommended operating conditions for UBT (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	түр†	MAX	UNIT
^t PLH	ЗА	20	5.8		7.9	
^t PHL		3B	5.5		7.7	ns
^t PLH	LE	20	5.9		8	
^t PHL	LE	3B	5.5		7.8	ns
t _{PLH}	CLKAB		5.9		8.1	
^t PHL	CLKAB	3B	5.5		7.7	ns
tr‡	Transition time, B port (10%–90%)		3.9	3.4	4.4	ns
t _f ‡	Transition time, B	port (90%–10%)	3.7	3.4	4.8	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

[‡] All t_r and t_f times are taken at the first receiver.

skew characteristics for bus transceiver for specific worst-case V_{CC} and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYP [†] MAX	UNIT
^t sk(LH)	1A or 2A	1B or 2B	1.7	
^t sk(HL)	TA OF ZA	IB UI 2B	2.1	ns
t _{sk(t)} §	1A or 2A	1B or 2B	1	ns
^t sk(pp)	1A or 2A	1B or 2B	0.2 2.1	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

§ tsk(t) - Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V_{CC} and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) [tsk(t)].



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driver in slot 1, with one receiver in slot 21 (minimum load) (continued)

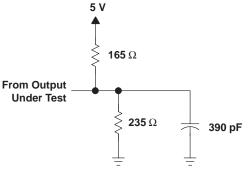
skew characteristics for UBT for specific worst-case V_{CC} and temperature within the recommended ranges of supply voltage and operating free-air temperature (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN TYPT MAX	UNIT
^t sk(LH)	24	3B	2	
^t sk(HL)	3A	30	2.3	ns
^t sk(LH)		20	2.1	
^t sk(HL)	CLKAB	3B	2.4	ns
t	3A	3B	1	
tsk(t)‡	CLKAB	3B	1	ns
+ + / _ >	3A	3B	0.2 2.5	
^t sk(pp)	CLKAB	3B	0.2 2.9	ns

[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. All values are derived from TI-SPICE models.

‡ t_{sk(t)} – Output-to-output skew is defined as the absolute value of the difference between the actual propagation delay for all outputs of the same packaged device. The specifications are given for specific worst-case V_{CC} and temperature and apply to any outputs switching in opposite directions, both low to high (LH) and high to low (HL) $[t_{sk(t)}]$.

By simulating the performance of the device using the VME64x backplane (see Figure 3), the maximum peak current in or out of the B-port output, as the devices switch from one logic state to another, was found to be equivalent to driving the lumped load shown in Figure 4.



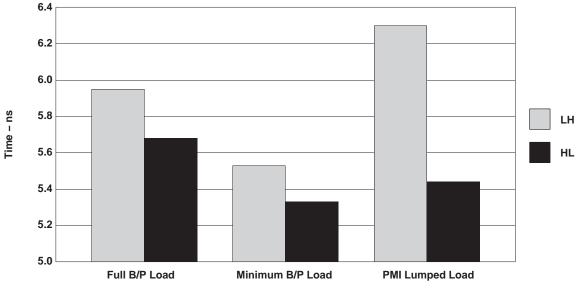
LOAD CIRCUIT

Figure 4. Equivalent AC Peak Output-Current Lumped Load



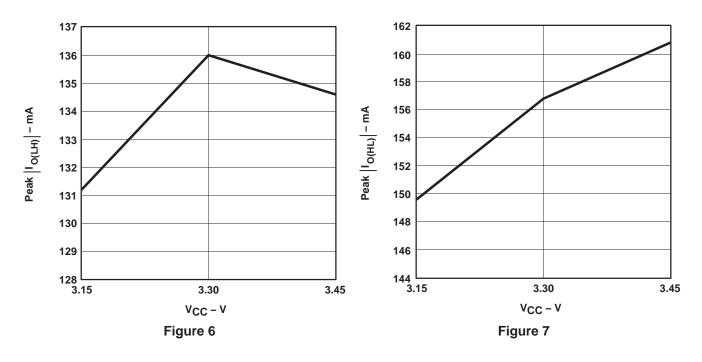
driver in slot 1, with one receiver in slot 21 (minimum load) (continued)

In general, the rise- and fall-time distribution is shown in Figure 5. Since VME devices were designed for use into distributed loads like the VME64x backplane (B/P), there are significant differences between low-to-high (LH) and high-to-low (HL) values in the lumped load shown in the PMI (see Figures 1 and 2).





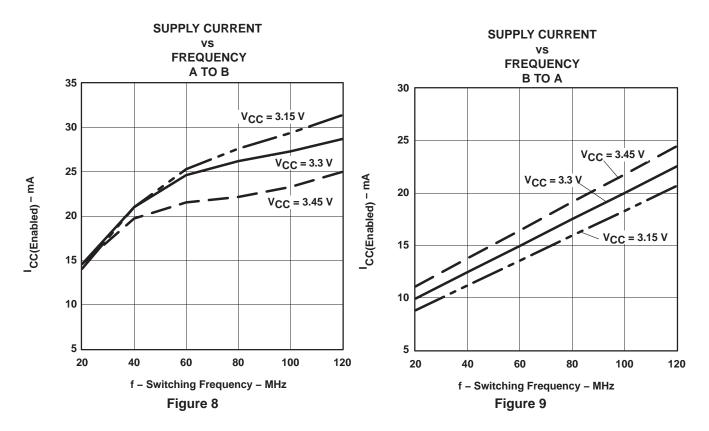
Characterization-laboratory data in Figures 6 and 7 show the absolute ac peak output current, with different supply voltages, as the devices change output logic state. A typical nominal process is shown to demonstrate the devices' peak ac output drive capability.





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TYPICAL CHARACTERISTICS





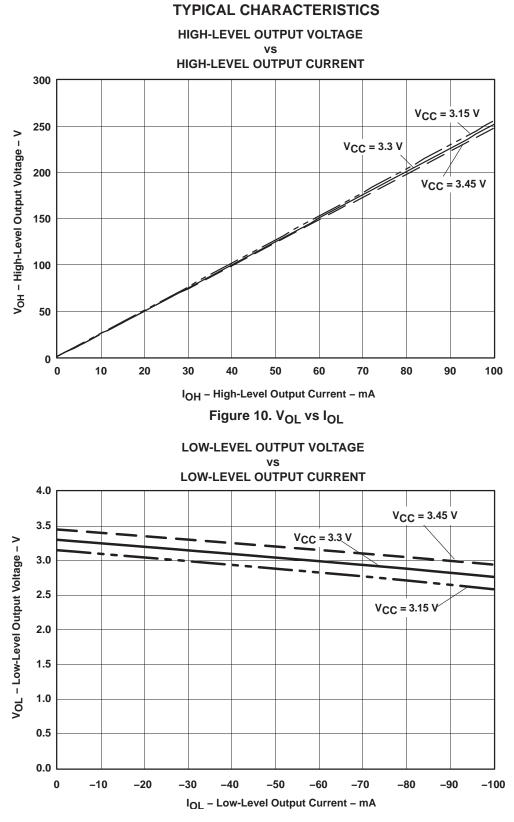


Figure 11. V_{OH} vs I_{OH}



VMEbus SUMMARY

In 1981, the VMEbus was introduced as a backplane bus architecture for industrial and commercial applications. The data-transfer protocols used to define the VMEbus came from the Motorola[™] VERSA bus architecture, which owed its heritage to the then recently introduced Motorola 68000 microprocessor. The VMEbus, when introduced, defined two basic data-transfer operations – single-cycle transfers consisting of an address and a data transfer, and a block transfer (BLT) consisting of an address and a sequence of data transfers. These transfers were asynchronous, using a master-slave handshake. The master puts address and data on the bus and waits for an acknowledgment. The selected slave either reads or writes data to or from the bus, then provides a data-acknowledge (DTACK*) signal. The VMEbus system data throughput was 40 Mbyte/s. Previous to the VMEbus, it was not uncommon for the backplane buses to require elaborate calculations to determine loading and drive current for interface design. This approach made designs difficult and caused compatibility problems among manufacturers. To make interface design easier and to ensure compatibility, the developers of the VMEbus architecture defined specific delays based on a 21-slot terminated backplane and mandated the use of certain high-current TTL drivers, receivers, and transceivers.

In 1989, multiplexing block transfer (MBLT) effectively increased the number of bits from 32 to 64, thereby doubling the transfer rate. In 1995, the number of handshake edges was reduced from four to two in the double-edge transfer (2eVME) protocol, doubling the data rate again. In 1997, the VMEbus International Trade Association (VITA) established a task group to specify a synchronous protocol to increase data-transfer rates to 320 Mbyte/s, or more. The unreleased specification, VITA 1.5 [double-edge source synchronous transfer (2eSST)], is based on the asynchronous 2eVME protocol. It does not wait for acknowledgement of the data by the receiver and requires incident-wave switching. Sustained data rates of 1 Gbyte/s, more than ten times faster than traditional VME64 backplanes, are possible by taking advantage of 2eSST and the 21-slot VME320 star-configuration backplane. The VME320 backplane approximates a lumped load, allowing substantially higher-frequency operation over the VME64x distributed-load backplane. Traditional VME64 backplanes with no changes theoretically can sustain 320 Mbyte/s.

From BLT to 2eSST – A Look at the Evolution of VMEbus Protocols by John Rynearson, Technical Director, VITA, provides additional information on VMEbus and can be obtained at www.vita.com.

DATE	DATE TOPOLOGY		DATA BITS	DATA TRANSFERS	PER SYSTEM	FREQUENCY (MHz)		
DATE		PROTOCOL	PER CYCLE	PER CLOCK CYCLE	(Mbyte/s)	BACKPLANE	CLOCK	
1981	VMEbus IEEE-1014	BLT	32	1	40	10	10	
1989	VME64	MBLT	64	1	80	10	10	
1995	VME64x	2eVME	64	2	160	10	20	
1997	VME64x	2eSST	64	2-No Ack	160–320	10–20	20–40	
1999	VME320	2eSST	64	2-No Ack	320-1000	20–62.5	40–125	

maximum data transfer rates

applicability

Target applications for VME backplanes include industrial controls, telecommunications, simulation, high-energy physics, office automation, and instrumentation systems.



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
74VMEH22501ADGGRE4	ACTIVE	TSSOP	DGG	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
74VMEH22501ADGGRG4	ACTIVE	TSSOP	DGG	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
74VMEH22501ADGVRE4	ACTIVE	TVSOP	DGV	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
74VMEH22501ADGVRG4	ACTIVE	TVSOP	DGV	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN74VMEH22501ADGGR	ACTIVE	TSSOP	DGG	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN74VMEH22501ADGVR	ACTIVE	TVSOP	DGV	48	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN74VMEH22501AGQLR	NRND	BGA MI CROSTA R JUNI OR	GQL	56	1000	TBD	SNPB	Level-1-240C-UNLIM
SN74VMEH22501AZQLR	ACTIVE	BGA MI CROSTA R JUNI OR	ZQL	56	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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PACKAGE OPTION ADDENDUM



18-Sep-2008

OTHER QUALIFIED VERSIONS OF SN74VMEH22501A : • Enhanced Product: SN74VMEH22501A-EP

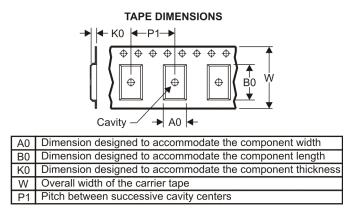
NOTE: Qualified Version Definitions:

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

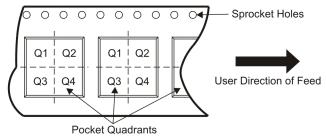
TEXAS INSTRUMENTS www.ti.com

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

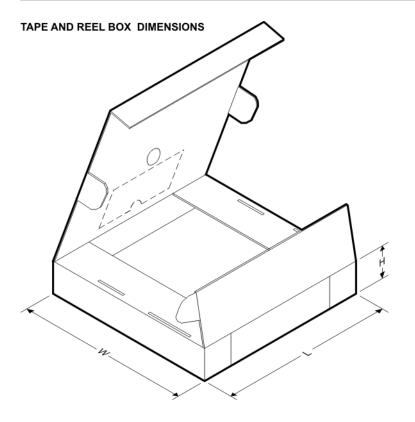


*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74VMEH22501ADGGR	TSSOP	DGG	48	2000	330.0	24.4	8.6	15.8	1.8	12.0	24.0	Q1
SN74VMEH22501ADGVR	TVSOP	DGV	48	2000	330.0	24.4	6.8	10.1	1.6	12.0	24.0	Q1
SN74VMEH22501AGQLR	BGA MI CROSTA R JUNI OR	GQL	56	1000	330.0	16.4	4.8	7.3	1.45	8.0	16.0	Q1
SN74VMEH22501AZQLR	BGA MI CROSTA R JUNI OR	ZQL	56	1000	330.0	16.4	4.8	7.3	1.45	8.0	16.0	Q1



PACKAGE MATERIALS INFORMATION

11-Mar-2008

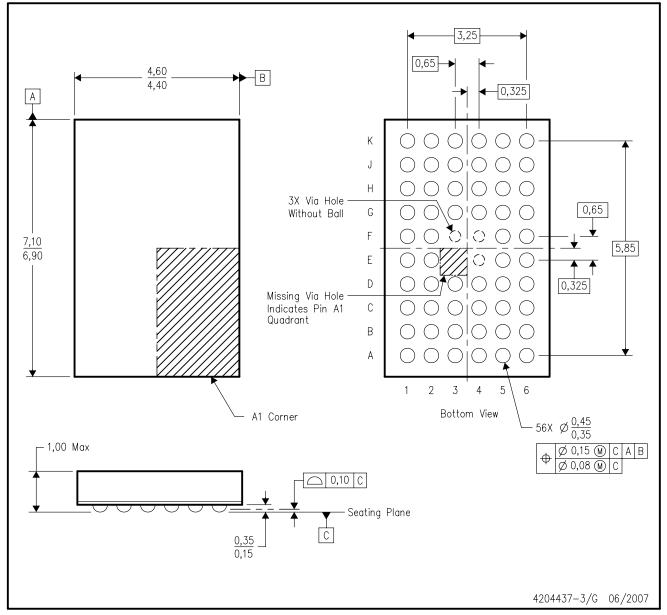


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74VMEH22501ADGGR	TSSOP	DGG	48	2000	346.0	346.0	41.0
SN74VMEH22501ADGVR	TVSOP	DGV	48	2000	346.0	346.0	41.0
SN74VMEH22501AGQLR	BGA MICROSTAR JUNIOR	GQL	56	1000	346.0	346.0	33.0
SN74VMEH22501AZQLR	BGA MICROSTAR JUNIOR	ZQL	56	1000	346.0	346.0	33.0

ZQL (R-PBGA-N56)

PLASTIC BALL GRID ARRAY



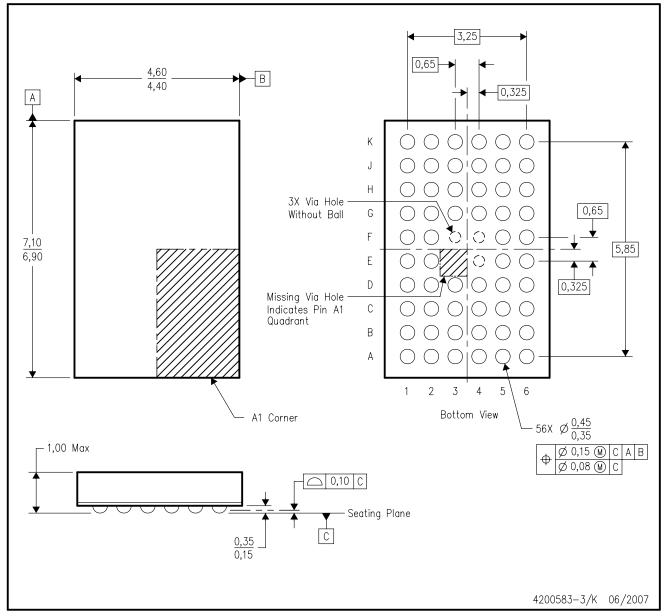
NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-285 variation BA-2.
- D. This package is lead-free. Refer to the 56 GQL package (drawing 4200583) for tin-lead (SnPb).



GQL (R-PBGA-N56)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-285 variation BA-2.
- D. This package is tin-lead (SnPb). Refer to the 56 ZQL package (drawing 4204437) for lead-free.



MECHANICAL DATA

MTSS003D - JANUARY 1995 - REVISED JANUARY 1998

DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold protrusion not to exceed 0,15.
- D. Falls within JEDEC MO-153



MECHANICAL DATA

PLASTIC SMALL-OUTLINE

MPDS006C - FEBRUARY 1996 - REVISED AUGUST 2000

DGV (R-PDSO-G**)

24 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.
- D. Falls within JEDEC: 24/48 Pins MO-153

14/16/20/56 Pins – MO-194



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